

N-Channel MOSFET MEM2302M3

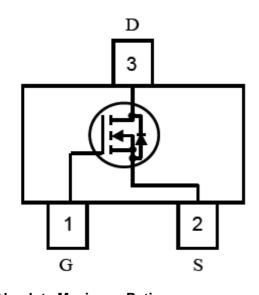
General Description

MEM2302M3G Series N-channel enhancement mode field-effect transistor ,produced with high cell density DMOS trench technology, which is especially used to minimize on-state resistance. This device particularly suits low voltage applications, and low power dissipation in a very small outline surface mount package.

Features

- 20V/3A
 - $R_{DS(ON)}$ = 29m Ω @ V_{GS} = 4.5V, I_D = 3A $R_{DS(ON)}$ = 36m Ω @ V_{GS} = 2.5V, I_D = 2A
- High Density Cell Design For Ultra Low On-Resistance
- Subminiature surface mount package:SOT23-3L

Pin Configuration



Typical Application

- Battery management
- High speed switch
- Low power DC to DC converter

Absolute Maximum Ratings

Parameter		Symbol	Ratings	Unit
Drain-Source Voltage		V_{DSS}	20V	V
Gate-Source Voltage		V_{GSS}	±8	V
Drain	T _A =25℃	1	3	۸
Current	T _A =70°C	l _D	2	- A
Pulsed Drain Current ^{1,2}		I _{DM}	15	А
Total Power	T _A =25℃	Pd	0.7	W
Dissipation	T _A =70°C	Fu	0.46	VV
operating junction temperature		T _j	150	$^{\circ}$ C
Storage Temperature Range		T _{stg}	-65/150	$^{\circ}$ C



Thermal Characteristics

Parameter	Symbol	Ratings	Unit
Thermal Resistance, Junction-to-Ambient	RθJA	140	°C/W

Electrical Characteristics

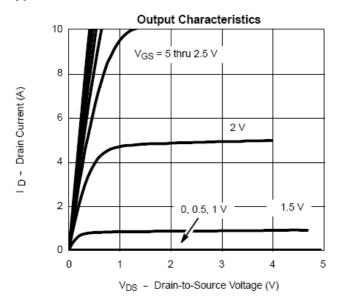
MEM2302M3

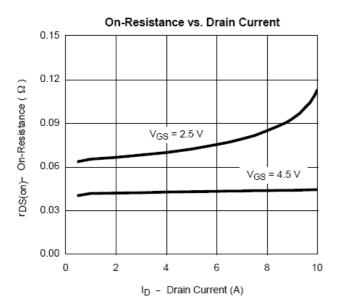
Parameter	Symbol	Test Condition	Min	Туре	Max	Unit				
Static Characteristics										
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	V _{GS} =0V, I _D =250uA	20	23		V				
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}$, $I_D = 250$ uA	0.51	0.53	0.85	V				
Gate-Body Leakage	I _{GSS}	$V_{DS}=0V$, $V_{GS}=8V$		1.6	100	nA				
Gale-Body Leakage		$V_{DS}=0V$, $V_{GS}=-8V$		-0.2	-100	nA				
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} =20V V _{GS} =0V		6.3	1000	nA				
Static Drain-Source On-Resistance	R _{DS(ON)}	V_{GS} =4.5V, I_{D} =3A		29	50	mΩ				
Static Dialii-Source Off-Resistance		V _{GS} =2.5V, I _D =2A		36	65	mΩ				
Forward Transconductance	g FS	$V_{DS} = 5 \text{ V}, I_{D} = 3.6 \text{A}$		8		S				
Source-drain (diode forward) voltage	V_{SD}	V _{GS} =0V,I _D =1.25A	0.4	0.7	1	V				
Dynamic Characteristics										
Input Capacitance	Ciss	$V_{DS} = 10 \text{ V},$		300						
Output Capacitance	Coss	$V_{GS} = 0 V$,		120		pF				
Reverse Transfer Capacitance	Crss	f = 1 MHz		80						
Switching Characteristics										
Turn-On Delay Time	td(on)	$V_{DD} = 15 \text{ V},$ $R_L = 2.8\Omega$		8	15					
Rise Time	tr	$I_D=3.6A$		50	80	ns				
Turn-Off Delay Time	td(off)	$V_{GEN} = 4.5V$,		15	60					
Fall-Time	tf	$Rg = 36\Omega$		10	25					
Total Gate Charge	Qg	$V_{DS} = 10V$,		4	10					
Gate-Source Charge	Qgs	$V_{GS} = 4.5 V$,		0.65		nc				
Gate-Drain Charge	Qgd	$I_{D} = 3.6A$		1.5						

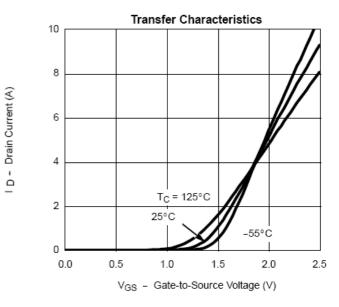
- 1. Repetitive rating, pulse width limited by junction temperature.
- 2_{\times} Pulse width <300us , duty cycle <0.5%.

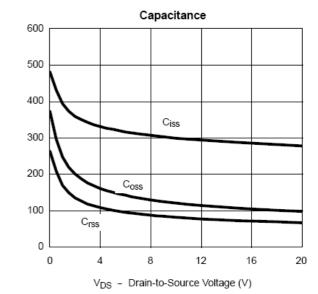


Typical Performance Characteristics



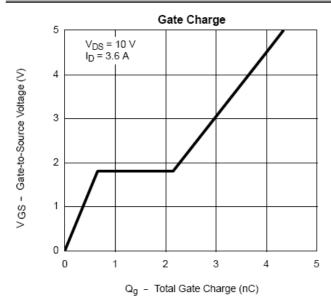


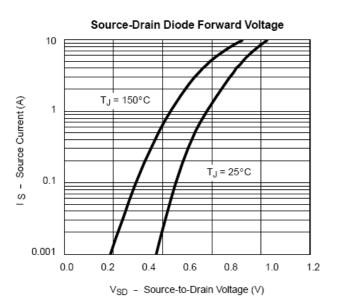


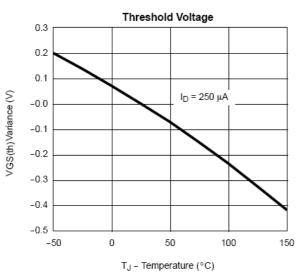


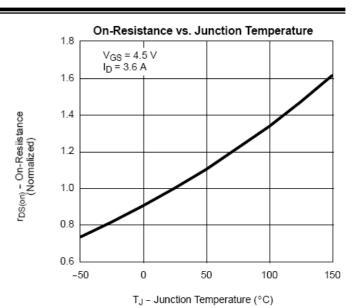
C - Capacitance (pF)

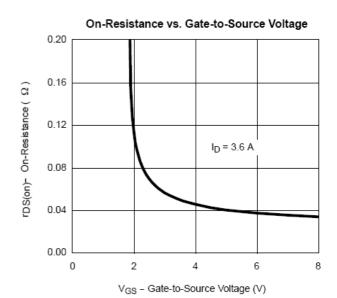


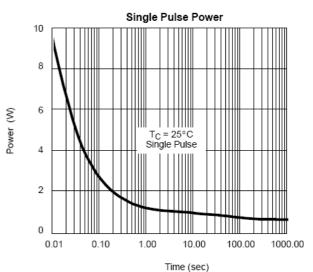




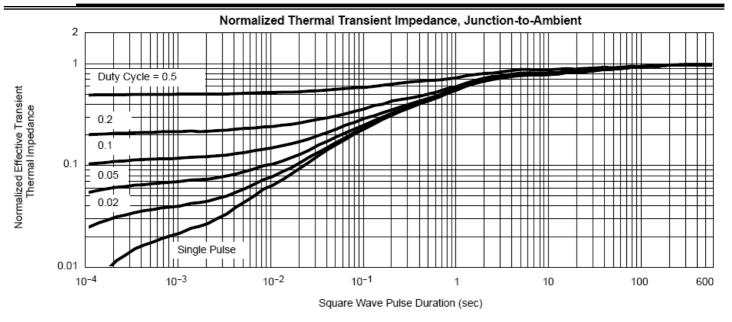






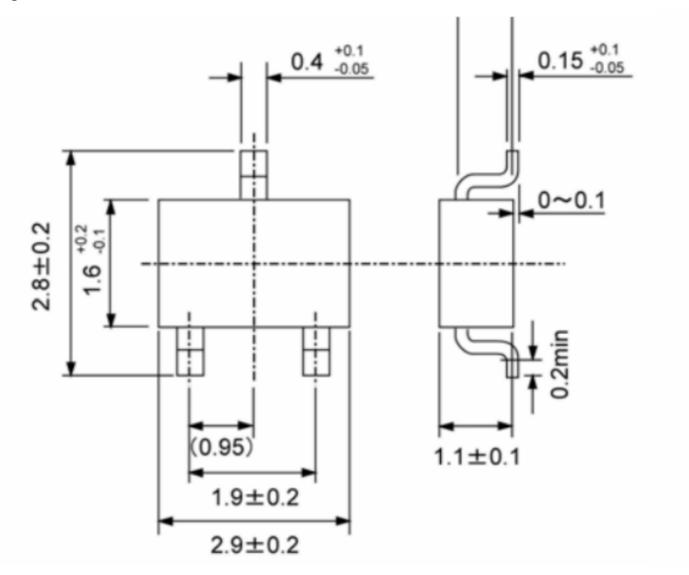








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